The HCCStar ASIC for the ATLAS ITk silicon strip detector: design and verification

Ben Rosser

University of Pennsylvania

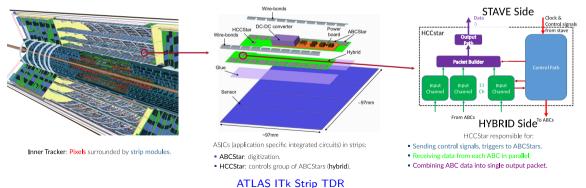
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Introduction to HCCStar Version 1

- Hybrid Controller Chip (HCCStar): ASIC being developed for ITK strip detector.
- Major operational problems seen when irradiating the first HCC prototype ("V0").
- New revision ("V1") currently being designed with improved radiation protection:
 - Increased mitigation against radiation-induced single event effects (SEEs) in digital logic.
 - Extensive **SEE simulation campaign** to verify mitigation works before fabricating the chip.



Ben Rosser (Penn)

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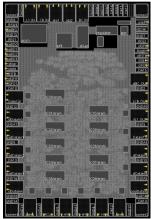
Digital Design

- HCC logic written at register transfer level in Verilog hardware description language.
- Verilog source code then compiled down into logic gates in synthesis process.
- Logic gates then mapped onto physical ASIC layout in place and route (PNR) process.

```
// Verilog source code
module example;
    input wire a;
    input wire b;
    output wire x;
    // x = a AND (NOT B)
    assign x = a && !b;
```

endmodule

$$X = A \land \overline{B}$$



Single Event Effects in ASICs

- Radiation can cause different kinds of single event effects (SEEs) in digital logic.
- SEEs can cause data corruption or errors that may require a reset to fix.
- Worried about two types of SEEs in the HCC: upsets and transients.

Single Event Upsets (SEUs):

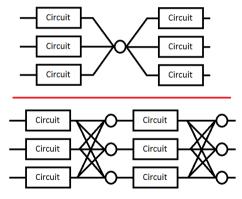
- Ionizing particle causes change of state.
- Affects flip-flops (Verilog reg type).
- **Permanent** change of state; lasts until corrected.
- Existing mitigation in prototype HCCStar design: attempted to protect critical area, like configuration registers and state machines.

Single Event Transients (SETs):

- Voltage pulse propagating through circuit causing signals to invert.
- Affects logic gates (modelled using Verilog wire type).
- Temporary pulse; inversion lasts for a short time (< 1 ns).
- Very limited existing mitigation in prototype HCCStar design.

Triplicating Digital Logic

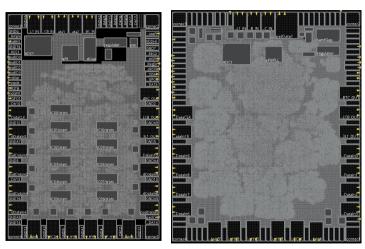
- Triplication, formally triple modular redundancy (TMR), used to protect against SEEs.
- Three copies of logic, use best-out-of-three majority voting to correct errors.
- Logic must be spaced far enough apart so one particle can't cause two SEEs at the same time.
- HCC V0 had some triplication of key flip-flops, like configuration registers and state machines.
- For protection against SETs: need to triplicate all logic – including majority voters – not just flip-flops.
- Full triplication **expensive**; three logic paths take up lots of space on physical chip.
- CERN tmrg tool used for automatic triplication.



Wikipedia

HCCStar V1 Design Changes

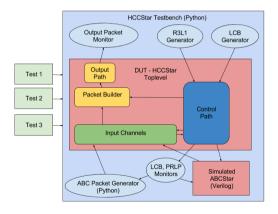
- HCC now **mostly** triplicated:
 - Physics data not fully protected in input channels.
 - Event ID is protected: SEEs can only corrupt one event.
- Some trade-offs necessary to reach this level of protection:
 - Memory buffers made smaller.
 - Input channel SRAMs reimplemented as FIFOs.
- Deglitcher circuits added for additional SET protection.
- Even with changes, could not route triplicated design without increasing chip width.



HCC widened from $3560\,\mu m$ (V0, left) to $4226\,\mu m$ (V1, right) in order to fit triplicated logic.

HCCStar Verification using Cocotb

- Digital logic verification done with Python-based testbench powered by cocotb.
- HCC runs on Cadence Xcelium simulator, controlled via cocotb library from Python.



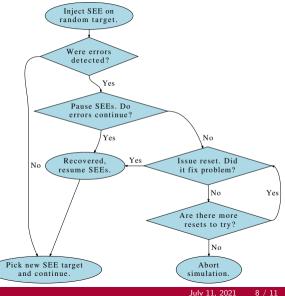
- Testbench built for V0, updated for V1:
 - Python implementations of serial protocols.
 - Python model of ABCStar data flow can generate packets in response to commands.
 - Tests are fully self-checking; full suite ran nightly for continuous integration.
- Testbench used for both **HCC-only** and **hybrid-level** simulations:
 - Real ABC used instead of Python model.
 - Used to simulate data flow with realistic HL-LHC conditions.
 - For V1, added support for module-level simulations with AMAC too.

Rapid SEE Simulations

- Cocotb testbench used to build rapid SEE simulation framework for HCC V1.
- Inject SEEs as fast as possible, maximize chances of finding problems.
- Run simple loop to probe chip behavior.
 - HCC-only: read out physics data and registers continuously.
 - Hybrid/module-level: run realistic data flow simulations, inject SEEs on HCC.
 - Run over post-PNR, gate-level design.

• Measure severity of any detected issues:

- First see if chip recovers without a reset.
- Attempt "soft" reset (no reconfiguration) before full "hard" reset.



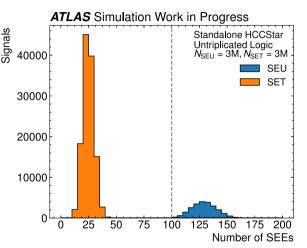
SEEs in Triplicated Logic

- SEEs on triplicated logic should cause no errors if TMR implemented correctly.
- Run separately over TMR, non-TMR parts of chip: confirm no errors in TMR simulation.
- Attempt to automatically detect potential triplication errors in real time:
 - Most TMR copies of flip-flops should be updated by majority voter every clock cycle.
 - Automatic check: look for redundant copies, check that all three agree after SEE.
 - This check **found problems**: after investigation, discovered some **real bugs in the chip**: signals not properly refreshed by voter could allow SEEs to accumulate over time.
 - Catches SEE vulnerabilities immediately, without waiting for data errors to be detected.

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SEEs in Untriplicated Logic

- Errors expected in non-TMR logic: use simulation to estimate rates.
 - Understand different failure modes.
 - How often are resets required?
 - Hard resets require reconfiguration: ensure they are rare.
- Perform high-statistics simulations with 100 SEEs per wire/flip-flop.
- Snapshot of current results:
 - In 3 days, reached SEU goal, performed 25% of SETs.
 - Low error rate, very few hard resets.
 - Results must be confirmed on final version before submission.



Injected 6M SEEs, found **18243** errors (0.3%), of which **3109** (17%) required a reset, **only 3** (0.016%) required hard reset.

- When designing particle detector electronics, SEE mitigation very important:
 - Add as much protection as possible!
 - Consider both SETs and SEUs when adding mitigation to a chip.
- Python-based verification using cocotb is a very powerful tool for ASIC design.
- SEE simulations using cocotb testbench are essential tool in SEE mitigation:
 - Used to confirm and track down problems seen during V0 irradiations.
 - Found and fixed many triplication-related bugs, removing potential SEE vulnerabilities.
 - Helping to build confidence in V1 radiation tolerance prior to submission.
- Thank you for your attention!

